

Class	Subclass	ISSUE CLASSIFICATION

PATENT NUMBER

U.S. Utility Patent Application

SCANNED	O.I.P.E.	PATENT DATE

APPLICATION NO. 09/811915	CONT/PRIOR	CLASS 324	SUBCLASS 750	ART UNIT 2858 2829	EXAMINER N. N. N.
APPLICANTS Wadgi Abadeer William Molsiff Edward Nowak					
TITLE Wafer level system for producing burn-in/screen. and reliability evaluations to be performed on all chips simultaneously without any wafer contacting					

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